Heraeus

Au HA3

Low Loop • High Reliability • Bumping



wire diameter together with a marked saving in precious metal costs.

Areas of application

High frequency bonding

Low temperature bonding

Low- and long-loop bonding

alloyed wire types contain a low percentage of alloying elements. This results in markedly higher wire strength, shorter heat affected zones and better thermal stability without a significant increase in electrical resistance. The increased wire strength,

while maintaining all other mechani-

cal properties, permits a reduction of

In contrast to doped Au wires,

High speed bonding

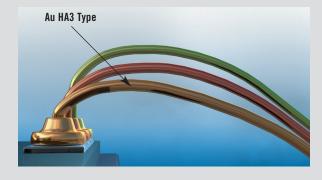
Ultra fine pitch bonding

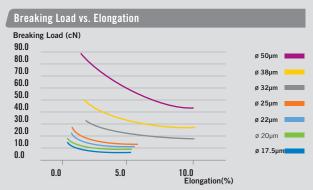
Ball bumping



Au HA3 Benefits

- High reliability wire type
- Increased strength, high loop stiffness
- Very good pull strengths and shear
- Long & low loop geometries
- Optimum stabilized phase formation
- High thermal stability



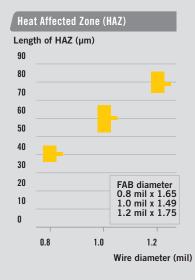


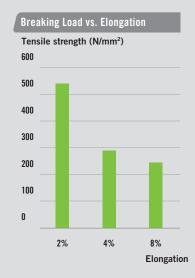
Recommended Technical Data of Au HA3									
Diameter	Microns (µm)	17.5	20	23	25	30	33	38	50
	Mils	0.7	8.0	0.9	1.0	1.2	1.3	1.5	2.0
Elongation	%	2 - 6	2 - 6	2 - 6	2 - 8	2 - 8	3 - 8	3 - 8	3 - 8
Breaking Load	cN	> 5	> 6	> 8	> 10	> 15	> 18	> 22	> 40

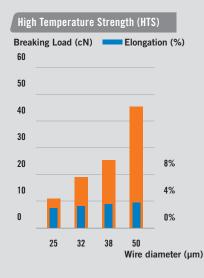
For other diameters, please contact Heraeus Bonding wires sales representative.

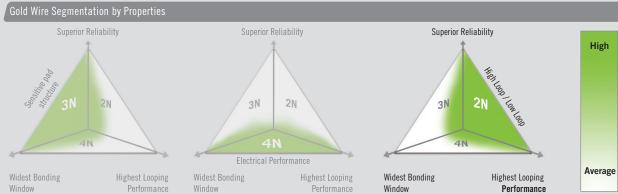
HA3 Characteristics for 25 µm diameter	
Non-Gold Elements	< 1.03wt %
Elastic Modulus	> 90 GPa
Heat Affected Zone (HAZ)	60 - 100µm
Melting Point	1063 °C
Density	19.2g / cm³

Heat Conductivity	3.03 W/cm.K
Electrical Resistivity	2.9μΩ-cm
Coeff. of Linear Expansion (20 $-$ 100 $^{\circ}\text{C})$	14.2 ppm / K
Fusing Current for 25 µm, dia 10 mm length (in air)	0.35 A









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